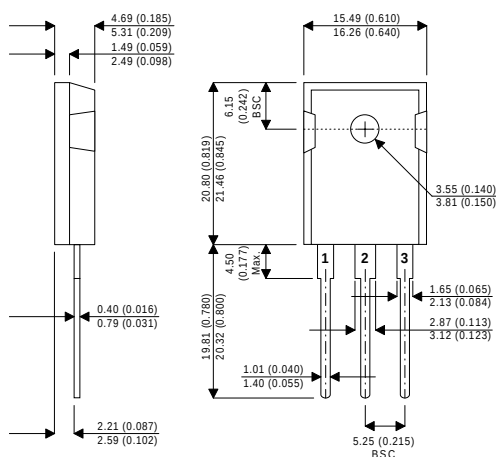


TO247–AD Package Outline.
Dimensions in mm (inches)



Pin 1 – Gate

Pin 2 – Drain

Pin 3 – Source

4TH GENERATION MOSFET

**N-CHANNEL
ENHANCEMENT MODE
HIGH VOLTAGE
POWER MOSFETS**

V_{DS} 500V

$I_{D(cont)}$ 28.0A

$R_{DS(on)}$ 0.20 Ω

ABSOLUTE MAXIMUM RATINGS ($T_{case} = 25^{\circ}\text{C}$ unless otherwise stated)

V_{DS}	Drain – Source Voltage	500	V
I_D	Continuous Drain Current	28	A
I_{DM}	Pulsed Drain Current ¹	112	A
V_{GS}	Gate – Source Voltage	± 30	V
P_D	Total Power Dissipation @ $T_{case} = 25^{\circ}\text{C}$	360	W
	Derate Linearly	2.9	W/ $^{\circ}\text{C}$
T_J, T_{STG}	Operating and Storage Junction Temperature Range	-55 to 150	$^{\circ}\text{C}$
T_L	Lead Temperature : 0.063" from Case for 10 Sec.	300	

STATIC ELECTRICAL RATINGS ($T_{case} = 25^{\circ}\text{C}$ unless otherwise stated)

	Characteristic	Test Conditions	Min.	Typ.	Max.	Unit
BV_{DS}	Drain – Source Breakdown Voltage	$V_{GS} = 0V, I_D = 250\mu\text{A}$	500			V
I_{DSS}	Zero Gate Voltage Drain Current ($V_{GS} = 0V$)	$V_{DS} = V_{DSS}$			250	μA
		$V_{DS} = 0.8V_{DSS}, T_C = 125^{\circ}\text{C}$			1000	
I_{GSS}	Gate – Source Leakage Current	$V_{GS} = \pm 30V, V_{DS} = 0V$			± 100	nA
$V_{GS(TH)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = 1.0\text{mA}$	2		4	V
$I_{D(ON)}$	On State Drain Current ²	$V_{DS} > I_{D(ON)} \times R_{DS(ON)} \text{ Max}$ $V_{GS} = 10V$	28			A
$R_{DS(ON)}$	Drain – Source On State Resistance ²	$V_{GS} = 10V, I_D = 0.5 I_D [\text{Cont.}]$			0.20	Ω

1) Repetitive Rating: Pulse Width limited by maximum junction temperature.

2) Pulse Test: Pulse Width < 380 μs , Duty Cycle < 2%

DYNAMIC CHARACTERISTICS

	Characteristic	Test Conditions	Min.	Typ.	Max.	Unit
C_{iss}	Input Capacitance	$V_{GS} = 0V$		2890	3500	pF
C_{oss}	Output Capacitance	$V_{DS} = 25V$		590	830	
C_{rss}	Reverse Transfer Capacitance	$f = 1MHz$		230	350	
Q_g	Total Gate Charge ³	$V_{GS} = 10V$		140	210	nC
Q_{gs}	Gate – Source Charge	$V_{DD} = 0.5 V_{DSS}$		18	27	
Q_{gd}	Gate – Drain (“Miller”) Charge	$I_D = I_D [Cont.] @ 25^\circ C$		75	110	
$t_{d(on)}$	Turn-on Delay Time	$V_{GS} = 15V$		19	38	ns
t_r	Rise Time	$V_{DD} = 0.5 V_{DSS}$		43	86	
$t_{d(off)}$	Turn-off Delay Time	$I_D = I_D [Cont.] @ 25^\circ C$		85	125	
t_f	Fall Time	$R_G = 1.8\Omega$		56	112	

SOURCE – DRAIN DIODE RATINGS AND CHARACTERISTICS

	Characteristic	Test Conditions	Min.	Typ.	Max.	Unit
I_S	Continuous Source Current	(Body Diode)			28	A
I_{SM}	Pulsed Source Current ¹	(Body Diode)			112	
V_{SD}	Diode Forward Voltage ²	$V_{GS} = 0V, I_S = -I_D [Cont.]$			1.3	V
t_{rr}	Reverse Recovery Time	$I_S = -I_D [Cont.], di_S / dt = 100A/\mu s$	215	430	860	ns
Q_{rr}	Reverse Recovery Charge	$I_S = -I_D [Cont.], di_S / dt = 100A/\mu s$	3	7	14	μC

SAFE OPERATING AREA CHARACTERISTICS

	Characteristic	Test Conditions	Min.	Typ.	Max.	Unit
SOA1	Safe Operating Area	$V_{DS} = 0.4V_{DSS}, t = 1 \text{ Sec.}$ $I_{DS} = P_D / 0.4V_{DSS}$	360			W
SOA2	Safe Operating Area	$V_{DS} = P_D / I_D [Cont.]$ $I_{DS} = I_D [Cont.], t = 1 \text{ Sec.}$	360			W
I_{LM}	Inductive Current Clamped		112			A

THERMAL CHARACTERISTICS

	Characteristic	Min.	Typ.	Max.	Unit
$R_{\theta JC}$	Junction to Case			0.34	$^\circ C/W$
$R_{\theta JA}$	Junction to Ambient			40	

1) Repetitive Rating: Pulse Width limited by maximum junction temperature.

2) Pulse Test: Pulse Width < 380 μs , Duty Cycle < 2%

3) See MIL-STD-750 Method 3471



CAUTION — Electrostatic Sensitive Devices. Anti-Static Procedures Must Be Followed.